

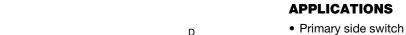
N-Channel 100 V (D-S) MOSFET

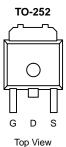
PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)		
	$0.055 \text{ at V}_{GS} = 10 \text{ V}$	25			
100	$0.057 \text{ at V}_{GS} = 4.5 \text{ V}$	25	21nC		
	0.070 at V _{GS} = 2.5 V	18			

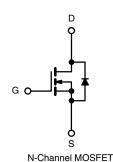
FEATURES

- TrenchFET® power MOSFET
- 100 % UIS tested









PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V _{DS}	100	V		
Gate-Source Voltage		V _{GS}		± 20	
	T _C = 25 °C		25		
Continuous Drain Current (T. 175 °C)	T _C = 70 °C		20		
Continuous Drain Current (T _J = 175 °C)	T _A = 25 °C	I _D	12 ^{b, c}		
	T _A = 70 °C		10 ^{b, c}		
Pulsed Drain Current	I _{DM}	80	A		
Continuous Courses Dunis Die de Coursest	T _C = 25 °C		25 ^e		
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	6.9 b, c		
Avalanche Current Pulse Single Pulse Avalanche Energy L = 0.1 n		I _{AS}	33		
		E _{AS}	55	mJ	
	T _C = 25 °C		83		
Marriagona Darron Dispiration	T _C = 70 °C	D	58	W	
Maximum Power Dissipation	T _A = 25 °C	P _D	70 ^{b, c}		
	T _A = 70 °C		50 ^{b, c}		
Operating Junction and Storage Temperature R	T _J , T _{sta}	-55 to +175	°C		

THERMAL RESISTANCE RATINGS							
PARAMETER	SYMBOL	TYPICAL	MAXIMUM	UNIT			
Maximum Junction-to-Ambient b, d	t ≤ 10 s	R _{thJA}	15	18	°C/W		
Maximum Junction-to-Case	Steady State	R_{thJC}	1.5	1.8	C/W		

Notes

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s
- d. Maximum under steady state conditions is 50 $^{\circ}\text{C/W}.$
- e. Calculated based on maximum junction temperature. Package limitation current is 50 A.

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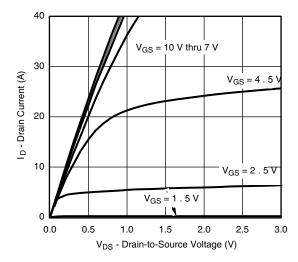
PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 050 A	-	165	-	m\//°C	
V _{GS(th)} Temperature Coefficient	ΔV _{GS(th)} /T _J	$I_{D} = 250 \mu A$	-	-11	-	mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	0.8	1.2	1.6	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$	-	-	± 100	nA	
Zero Gate Voltage Drain Current	Inno	V _{DS} = 100 V, V _{GS} = 0 V	-	-	1	μА	
Zero date voltage Drain Gurrent	I _{DSS}	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$	-	-	10	μΑ	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	25		-	Α	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, I_{D} = 12 \text{A}$	-		0.055	- Ω	
Drain Course on State Resistance	1 (DS(on)	V_{GS} =4.5 V, I_D =8A			0.057		
Forward Transconductance a	9fs	$V_{DS} = 15 \text{ V}, I_{D} = 12 \text{ A}$	-	25	-	S	
Dynamic ^b							
Input Capacitance	C _{iss}		-	-	2300	pF	
Output Capacitance	Coss	$V_{DS} = 12 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	-	180		
Reverse Transfer Capacitance	C _{rss}		-	-	60		
Total Gate Charge	Q_g		-	21	-	nC	
Gate-Source Charge	Q _{gs}	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 12 \text{ A}$	-	10	-		
Gate-Drain Charge	Q_{gd}		-	9	-		
Gate Resistance	R_g	f = 1 MHz	-	1.5	-	Ω	
Turn-On Delay Time	t _{d(on)}		-	10	15		
Rise Time	t _r	$V_{DD} = 50 \text{ V}, R_1 = 5 \Omega$	-	10	15	ns	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$	-	15	25		
Fall Time	t _f		-	10	15		
Drain-Source Body Diode Characteristics	S			L			
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C	-	-	50		
Pulse Diode Forward Current ^a	I _{SM}		-	-	40	A	
Body Diode Voltage	V_{SD}	I _S = 10 A	-	0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}		-	50	75	ns	
Body Diode Reverse Recovery Charge	Q _{rr}		-	100	150	nC	
Reverse Recovery Fall Time	t _a	$I_F = 10 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$	-	38	-		
Reverse Recovery Rise Time	t _b		_	12	_	ns	

Note

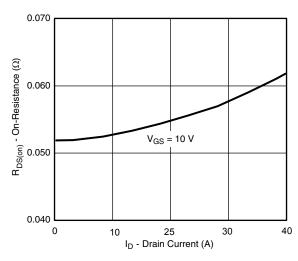
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

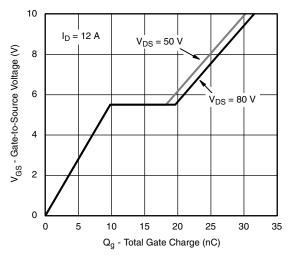




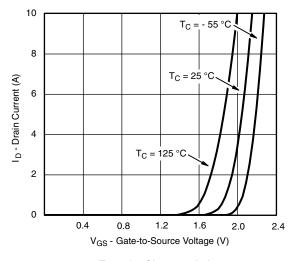




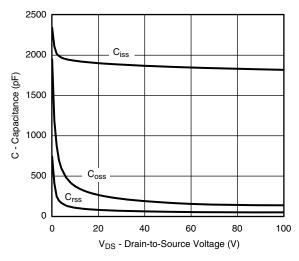
On-Resistance vs. Drain Current



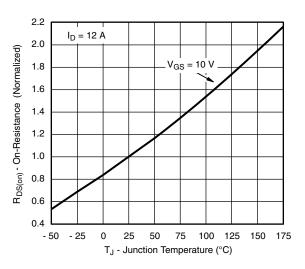
Gate Charge



Transfer Characteristics

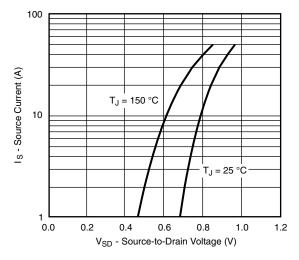


Capacitance

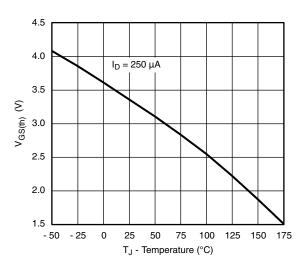


On-Resistance vs. Junction Temperature

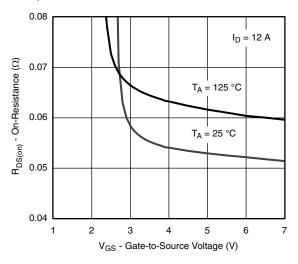




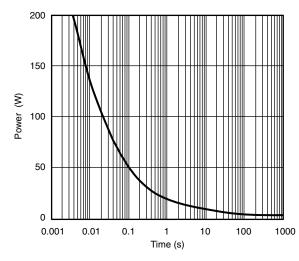
Source-Drain Diode Forward Voltage



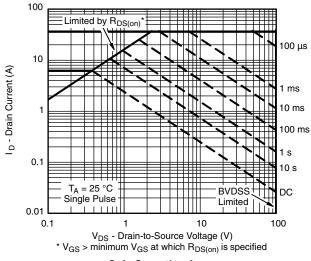
Threshold Voltage



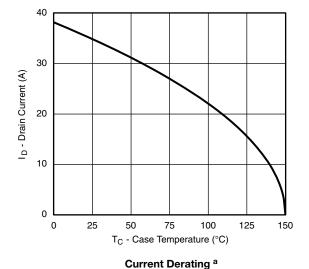
R_{DS(on)} vs. V_{GS} vs. Temperature

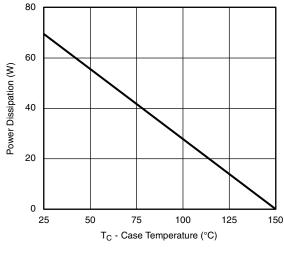


Single Pulse Power, Junction-to-Ambient







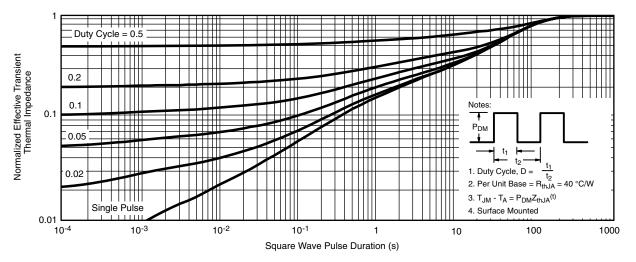


Power Derating

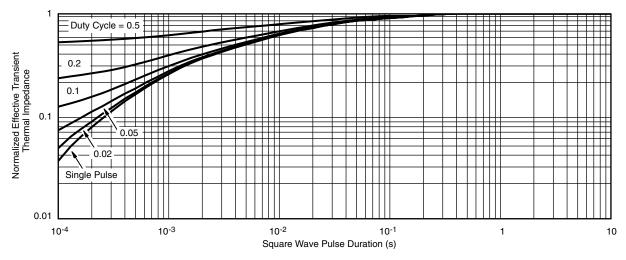
Note

a. The power dissipation P_D is based on T_J (max.) = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





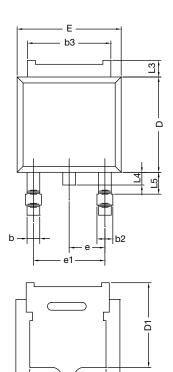
Normalized Thermal Transient Impedance, Junction-to-Ambient

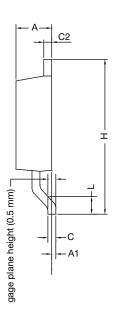


Normalized Thermal Transient Impedance, Junction-to-Case



TO-252AA Case Outline





	MILLIN	METERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
Α	2.18	2.38	0.086	0.094	
A1	-	0.127	-	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	4.10	-	0.161	-	
Е	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28 BSC		0.090 BSC		
e1	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	-	0.040	
L5	1.01	1.52	0.040	0.060	
ECN: T16-0236-Rev. P. 16-May-16					

ECN: T16-0236-Rev. P, 16-May-16 DWG: 5347

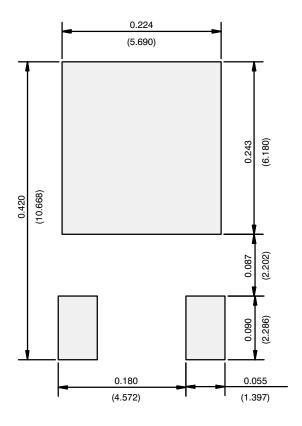
Notes

• Dimension L3 is for reference only.

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RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)



Recommended Minimum Pads Dimensions in Inches/(mm)



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